Ab-initio modeling of Conductive channel in Cu – Al$_2$O$_3$ conductive bridge RRAM

James A Dawson$^1$, John Robertson $^1$

$^1$ Engineering Dept, Cambridge University, Cambridge CB2 1PZ, UK
Phone: +44-1223-748331 E-mail: jr@eng.cam.ac.uk

Abstract
The narrower, more conductive channel of Cu-based CB-RRAM compared to the channel in Oxygen vacancy based Ox-RAM is shown by ab-initio simulations to arise from the higher Cu-Cu coordinations and tighter bonding, than between the equivalent vacancy clusters.

1. Introduction
There is a rapid development of non-volatile semiconductor based memory technologies such as Resistive random access memory (RRAM) to complement Flash memory. There are two main classes of RRAM, one based on oxygen vacancies in oxides such as HfO$_2$ (Ox-RRAM), and one based Cu filaments or ‘conductive bridges’ in an oxide host such as amorphous (a-)Al$_2$O$_3$ (CB-RRAM). Ox-RRAM has the advantage than it uses well known CMOS compatible oxides like HfO$_2$. However, OX-RRAM has a relatively small ON / OFF resistance window. The ON and OFF states are characterized by resistance distributions that overlap at the 3σ level (σ being the variance of this distribution.) In contrast, CB-RRAM contains Cu, but has a much wider ON/OFF window, so the distributions do not overlap [1,2]. Belamonte [3] noted that CBRAM had a denser filament.

It is therefore of interest to understand the nature of the conductive filament in each case, using ab-initio atomic simulations. We recall that Kamiya et al [4,5] considered the pairing attraction between two O vacancies in HfO$_2$, Al$_2$O$_3$ and TiO$_2$ to understand filament formation in oxides. We find that the Cu filament in CBRAM is denser because of the much higher Cu coordination numbers and stronger Cu-Cu bonding in the CBRAM case. Previous analyses by other groups [7-9] was less detailed.

2. Methods
The calculations use the plane wave, pseudopotential code CASTEP. We first study the energetics and defect energy levels of Cu interstitials in amorphous (a-) Al$_2$O$_3$ network. We use the 0-Al$_2$O$_3$ polymorph to represent a-Al$_2$O$_3$, as it has a similar density, coordination and band gap. We then consider the binding between two Cu atoms and Cu atom clusters, as a function of separation and coordination.

3. Results and Discussion
We first evaluate the energies of single Cu$^+$ ions at various interstitial sites in the Al$_2$O$_3$. We find three main low energy sites, as denoted in Fig. 1. Fig. 1 shows the defect formation energy of Cu ions at these sites as a function of the Fermi energy referred to the valence band maximum, for the PBE exchange correlation functional. The Cu$^{1+}$ state is seen to be the most stable site for most E$_F$. We then recalculated this for the I$^0$ site in the screened exchange hybrid functional which corrects the GGA band gap error, Fig. 2. E$_F$ in this diagram gives the work function of metallic Cu, referred to the vacuum level by the known electron affinity of Al$_2$O$_3$. Fig 3 shows the partial density of states (PDOS) of isolated Cu sites in the different charge states. They are insulating.

Fig. 4 shows the binding energy of two Cu interstitials as a function of their separation in the Cu$^0$, Cu$^+$ and Cu$^{2+}$ states. We see that there is strong binding for the Cu$^0$ state. The bond length in metallic Cu is 2.50 Å for reference.

Fig. 5 shows the binding energy between a Cu site increasing from 2 atoms to ever large clusters of a chain then a rod, for each charge state. It compares this with the case of O vacancies in TiO$_2$ [4] or HfO$_2$. In the O vacancy case, two open-shell V$^+$ vacancy sites bind together to form a ‘covalent bond’, with paired electrons. This is then a closed shell, so pairs have little more binding to make larger clusters. In contrast, for Cu$^0$ sites, the Cu-Cu bonding is of metallic character. This has longer range, and does not saturate at a coordination number of 2, but continues to increase, with an example in Fig 7. Thus, the Cu filament can bond as in metallic Cu, and form a long, dense rod. Thus, for a given ON current (compliance), the filament is denser and narrower, giving a higher ON/OFF ratio, as seen experimentally [3].

3. Conclusions
Based on atomic simulations, it is argued that the stronger, longer range and higher coordinated bonding between Cu sites than O vacancies makes for a d, narrower denser filament, leading to higher ON/OFF ratio.

Acknowledgements
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References
Fig. 1. Defect energy vs. Fermi energy for Cu at 3 different interstitial sites, in PBE.

Fig. 2. Defect energy vs. Fermi energy in SX, for different Fermi energies, referred to vacuum level.

Fig. 3. PDOS of Cu0, Cu+ and Cu2+ states of isolated Cu sites in Al2O3.

Fig. 4. Binding energy between pairs of Cu sites vs separation, for different charge states.

Fig. 5. Binding energy of Cu sites compared to O vacancies, for increasing clustering.

Fig. 6. Top and side view of a model Cu filament through the Al2O3 host. Cu=blue, Oxygen =red, Al=grey.